



SLOVENSKI STANDARD
SIST EN 61340-4-7:2017
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Elektrostatika - 4-7. del: Standardne preskusne metode za posebno uporabo - Ionizacija (IEC 61340-4-7:2017)

Electrostatics - Part 4-7: Standard test methods for specific applications - Ionization (IEC 61340-4-7:2017)

iTeh STANDARD PREVIEW

Electrostatique - Partie 4-7: Méthodes d'essai normalisées pour des applications spécifiques - Ionisation (IEC 61340-4-7:2017)

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**Electrostatics - Part 4-7: Standard test methods for specific applications - Ionization
(IEC 61340-4-7:2017)**

Électrostatique - Partie 4-7: Méthodes d'essai normalisées
pour des applications spécifiques - Ionisation
(IEC 61340-4-7:2017)

Elektrostatik - Teil 4-7: Standard-Prüfverfahren für spezielle
Anwendungen - Ionisation
(IEC 61340-4-7:2017)

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European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

CEN-CENELEC Management Centre: Avenue Marnix 17, B-1000 Brussels

EN 61340-4-7:2017**European foreword**

The text of document 101/521/FDIS, future edition 2 of IEC 61340-4-7, prepared by IEC/TC 101 "Electrostatics" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN 61340-4-7:2017.

The following dates are fixed:

- latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2017-11-10
- latest date by which the national standards conflicting with the document have to be withdrawn (dow) 2020-02-10

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Endorsement notice

The text of the International Standard IEC 61340-4-7:2017 was approved by CENELEC as a European Standard without any modification.

In the official version, for Bibliography, the following note has to be added for the standard indicated :

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Part 4-7: Standard test methods for specific applications – Ionization
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Électrostatique –
Partie 4-7: Méthodes d'essai normalisées pour des applications spécifiques –
Ionisation

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CONTENTS

FOREWORD.....	4
INTRODUCTION.....	6
1 Scope.....	7
2 Normative references	7
3 Terms and definitions	7
4 Test fixture and instrumentation.....	9
5 Specific requirements for equipment categories.....	11
5.1 Specific requirements for all ionization equipment.....	11
5.2 Room ionization	12
5.3 Laminar flow hood ionization.....	14
5.4 Work surface ionization.....	16
5.5 Compressed gas ionizers – Guns and nozzles	19
Annex A (informative) Theoretical background and additional information on the standard test method for the performance of ionizers.....	21
A.1 Introductory remarks	21
A.2 Air ions	21
A.3 Mobility and ion current.....	21
A.4 Neutralization current.....	21
A.5 Neutralization rate	22
A.6 Ion depletion and field suppression.....	22
A.7 Charged plate monitor and charge neutralization	22
A.8 Relationship between charged plate monitor decay time and actual object.....	23
A.9 Offset voltage	23
A.10 Preparation of test area	23
A.11 Ion transport in airflow	24
A.12 Obstruction of airflow around the charged plate monitor.....	24
A.13 Effect of “air blanket”	24
A.14 Sources of measurement error	25
A.14.1 Typical decay time variability	25
A.14.2 Plate isolation.....	25
A.14.3 Charging voltage	25
A.14.4 Materials near the plate	25
A.14.5 Other field-producing devices in test area.....	25
A.14.6 Effect of offset voltage on decay time	25
A.15 Importance of ionization equipment maintenance	26
Annex B (normative) Method of measuring the capacitance of an isolated conductive plate	27
B.1 Method	27
B.2 Equipment	27
B.3 Procedure	27
B.4 Example.....	27
B.5 Sources of error	28
B.5.1 Measuring equipment	28
B.5.2 Poor plate isolation.....	28
B.5.3 Objects in the environment	29
B.5.4 Stray capacitance	29
Annex C (informative) Safety considerations.....	30

C.1	General.....	30
C.2	Electrical.....	30
C.3	Ozone.....	30
C.4	Radioactive.....	30
C.5	X-ray.....	30
C.6	Installation	30
	Bibliography.....	31
	Figure 1 – Charged plate monitor components for non-contacting plate measurement	10
	Figure 2 – Charged plate monitor components for contacting plate measurement	10
	Figure 3 – Conductive plate detail for the non-contacting CPM	11
	Figure 4 – Conductive plate detail for the voltage follower CPM.....	11
	Figure 5 – Test locations for room ionization – AC grids and DC bar systems	13
	Figure 6 – Test locations for room ionization – Single polarity emitter systems	13
	Figure 7 – Test locations for room ionization – Dual DC line systems.....	14
	Figure 8 – Test locations for room ionization – Pulsed DC emitter systems	14
	Figure 9 – Test locations for vertical laminar flow hood – Top view	15
	Figure 10 – Test locations for vertical laminar flow hood – Side view	15
	Figure 11 – Test locations for horizontal laminar flow hood – Top view	16
	Figure 12 – Test locations for horizontal laminar flow hood – Side view	16
	Figure 13 – Test locations for benchtop ionizer – Top view	17
	Figure 14 – Test locations for benchtop ionizer – Side view	18
	Figure 15 – Test locations for overhead ionizer – Top view	18
	Figure 16 – Test locations for overhead ionizer – Side view	19
	Figure 17 – Test locations for compressed gas ionizer (gun or nozzle) – Side view.....	20
	Table 1 – Test set-ups and test locations/points (TP).....	12
	Table B.1 – Example measurement data	28

INTERNATIONAL ELECTROTECHNICAL COMMISSION

ELECTROSTATICS –

Part 4-7: Standard test methods for specific applications –
Ionization

FOREWORD

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International Standard IEC 61340-4-7 has been prepared by IEC technical committee 101: Electrostatics.

This second edition cancels and replaces the first edition, published in 2010, and constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- the use of contacting plate voltage measurements in addition to the previous non-contacting plate voltage measurements has been added. Charged plate monitors (CPMs) using this technology have been in use in the industry for many years.

The text of this standard is also based on the following documents:

FDIS	Report on voting
101/521/FDIS	101/524/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts in the IEC 61340 series, published under the general title *Electrostatics*, can be found on the IEC website.

The committee has decided that the contents of this publication will remain unchanged until the stability date indicated on the IEC website under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

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INTRODUCTION

Grounding is the primary method used to limit static charge when protecting electrostatic discharge sensitive items in the work environment. However, grounding methods are not effective in removing static charges from the surfaces of non-conductive (insulative) or isolated conductive materials. Air ionization techniques, by means of ionizer systems, can be utilized to reduce this charge.

The preferred way of evaluating the ability of an ionizer to neutralize a static charge is to directly measure the rate of charge decay. Charges to be neutralized may be located on insulators as well as on isolated conductors. It is difficult to charge an insulator reliably and repeatably. Charge neutralization is more easily evaluated by measuring the rate of decay of the voltage of an isolated conductive plate. The measurement of this decay should not interfere with or change the nature of the actual decay. Four practical methods of air ionization are addressed in this document:

- a) radioactive emission;
- b) high-voltage corona from a.c. electric fields;
- c) high-voltage corona from d.c. electric fields;
- d) soft X-ray emission.

This part of IEC 61340 provides test methods and procedures that can be used when evaluating ionization equipment. The objective of the test methods is to generate meaningful, reproducible data. The test methods are not meant to be a recommendation for any particular ionizer configuration. The wide variety of ionizers, and the environments within which they are used, will often require test methods different from those described in this document. Users of this document should be prepared to adapt the test methods as required to produce meaningful data in their own application of ionizers.

Similarly, the test conditions chosen in this document do not represent a recommendation for acceptable ionizer performance. There is a wide range of item sensitivities to static charge. There is also a wide range of environmental conditions affecting the operation of ionizers. Performance specifications should be agreed upon between the user and manufacturer of the ionizer in each application. Users of this document should be prepared to establish reasonable performance requirements for their own application of ionizers.

Annex B provides a method for measuring capacitance of the isolated conductive plate.

ELECTROSTATICS –

Part 4-7: Standard test methods for specific applications – Ionization

1 Scope

This part of IEC 61340 provides test methods and procedures for evaluating and selecting air ionization equipment and systems (ionizers).

This document establishes measurement techniques, under specified conditions, to determine offset voltage (ion balance) and decay (charge neutralization) time for ionizers.

This document does not include measurements of electromagnetic interference (EMI), or the use of ionizers in connection with ordnance, flammables, explosive items or electrically initiated explosive devices.

As contained in this document, the test methods and test conditions can be used by manufacturers of ionizers to provide performance data describing their products. Users of ionizers are urged to modify the test methods and test conditions for their specific application in order to qualify ionizers for use, or to make periodic verifications of ionizer performance. The user will decide the extent of the data required for each application.

CAUTION: Procedures and equipment described in this document can expose personnel to hazardous electrical and non-electrical conditions. Users of this document are responsible for selecting equipment that complies with applicable laws, regulatory codes and both external and internal policy. Users are cautioned that this document cannot replace or supersede any requirements for personnel safety.

2 Normative references

There are no normative references in this document.

3 Terms and definitions

For the purposes of this document, the following terms and definitions apply.

ISO and IEC maintain terminological databases for use in standardization at the following addresses:

- IEC Electropedia: available at <http://www.electropedia.org/>
- ISO Online browsing platform: available at <http://www.iso.org/obp>

3.1

air conductivity

ability of air to conduct (pass) an electric current under the influence of an electric field

3.2

air ions

molecular clusters of about ten molecules (water, impurities, etc.) bound by polarization forces to a singly charged oxygen or nitrogen molecule

3.3**charge decay**

decrease and/or neutralization of a net electrostatic charge

3.4**charged plate monitor**

CPM

instrument using a charged metal plate of a defined capacitance and geometry which is discharged in order to measure charge dissipation/neutralization properties of products or materials

Note 1 to entry: This note applies to the French language only.

3.5**compressed gas ionizer**

ionization device that can be used to neutralize charged surfaces and/or remove surface particles with pressurized gas

Note 1 to entry: This type of ionizer may be used to ionize the gas within production equipment.

3.6**corona**

production of positive or negative ions by a very localized high electric field

Note 1 to entry: The field is normally established by applying a high voltage to a conductor in the shape of a sharp point or wire.

3.7**decay rate**

decrease of charge or voltage per unit time

3.8**decay time**

time necessary for a voltage (due to an electrostatic charge) to decay from an initial value to some chosen final value

3.9**emitter**

conducting sharp object, usually a needle or wire, which will cause a corona discharge when kept at a high potential

3.10**horizontal laminar flow**

non-turbulent airflow in a horizontal direction

3.11**ionizer**

device designed to generate positive and/or negative air ions

3.12**isolated conductor**

non-grounded conductor

3.13**laminar flow hood ionization**

device or systems that provide local area ionization coverage in vertical or horizontal laminar flow hoods or benches

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